Zeta 20

3D Profiler & Optical Imaging

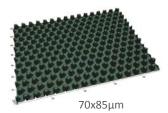
- True Color 3D Imaging
- Sub-micron Metrology:
 Step height, linear & areal roughness, angle, dimensions
- High Roughness and Low Reflectivity samples
- Deep channels and other high-aspect ratio features
- Transmissive (backlight) stage option
- Film thickness & DIC options
- Versatile application software



The Zeta-20 is a fully-integrated surface measurement system that provides advanced 3D imaging and metrology features in a flexible, cost-effective package. Zeta Instruments' proprietary ZDotTM technology enables rapid imaging of PSS, solar cells, fluid microchannels, and other surfaces that more costly

systems cannot easily handle. Since there is no sample contact and very little system maintenance, Zeta metrology systems deliver an unparalleled level of performance with minimal cost of ownership.

Zeta 20 Applications



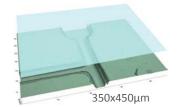
LED/PSS

Measure diameter, pitch and height of LED substrate features automatically; image pre-etch PR and postetch cones/domes



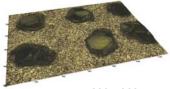
Solar Cell

Contact finger, width, height & volume. High dynamic range enables imaging of high-reflectance metal on low reflectance nitride; measure AR films as well as metal deposition



Bio-Tech/Microfluidics

High-aspect ratio, deep channels in bio-chips can be easily dimensioned and imaged over wide fields of view. Multiple surfaces such as cover glasses or transparent fluids can also be imaged



800x1300μm

Precision Polishing

Extreme features and very high roughness surfaces like diamond conditioning discs can be easily imaged and measured

System Specifications

Optical Specifications					
	5x	10x	20x	50x	100x
Z res (μm)	5.90	1.50	0.50	0.10	0.07
N.A.	0.15	0.30	0.45	0.80	0.90
XY Res. (μm)	2.20	1.10	0.75	0.42	0.40
FOV (μm)¹	1920x1440	960x720	480x360	192x144	96x72
FOV (μm) ²	5029x3771	2514x1886	1257x943	503x377	251x189
Accuracy	±2.5%³				
Repeatability	Better than 1.5% (1σ/Mean)³				

Dimensions (mm)

Microscope: 305 x 406 x 559 *Computer:* 381 x 457 x 102

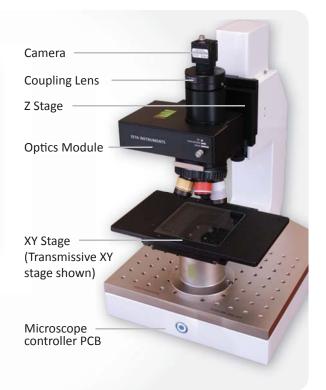
Monitor: 559 x 406 x 127 **Total Weight:** 65 lbs/29.5 kg

Operating Specifications

Voltage: 100 - 230 VAC

Current: 2A

Op. Temp.: 18 - 30°C, noncondensing, ± 1°C per hour



Typical System Configuration

Microscope Sub-system

Light Source: High-brightness white LED Objectives: 5x, 10x, 20x, 50x, 100x

Coupling Lens: 0.5x

Manual Stage: 100mm x 100mm XY travel
Z-Stage: 30mm total vertical travel
Camera: 1024 x 768, 1/3" CCD

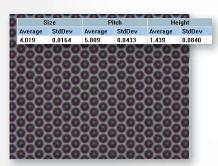
Computer Control Sub-system

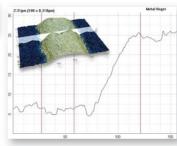
Processor: Intel Core2 Duo (2.5GHz minimum)

RAM: 3GB HDD: 320GB

Display: 22" Widescreen LCD monitor

(1680 x 1050)





LED PSS Size & Pitch

Solar Finger Profile

Zeta 3D Measurement Software

Live video imaging

Rapid data capture (<1 minute per site)

3D surface visualization:

Tilt, Rotation, Zoom, Filtering Feature volume calculation

2D surface analysis:

Feature size, diameter, area Pattern pitch, standard deviation

Areal roughness

Box height (areal avg step height)

Profilometry

Step height

Roughness parameters Multiple cross-sections

Averaging measurement cursors
Point-to-point measurement markers
Slope & waviness compensation

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¹ 1/3" CCD Camera with 0.5x Coupling Lens

² 2/3" CCD Camera with 0.35x Coupling Lens

 $^{^3}$ Static repeatability/accuracy based on VLSI 8 μ m step height standard, 100x/0.9NA objective